

## SUPPLEMENTARY MATERIAL

### Electrochemical Performance of Electrochemical Capacitors

### Prepared with Activated Carbons from Sugar Cane Bagasse

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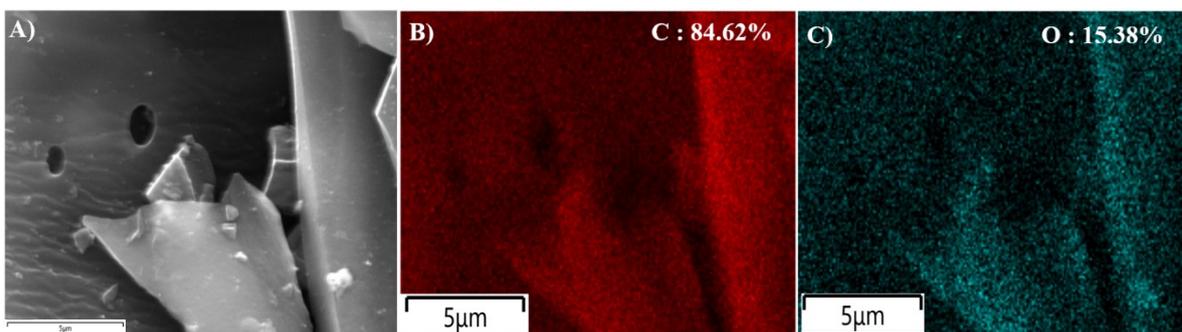
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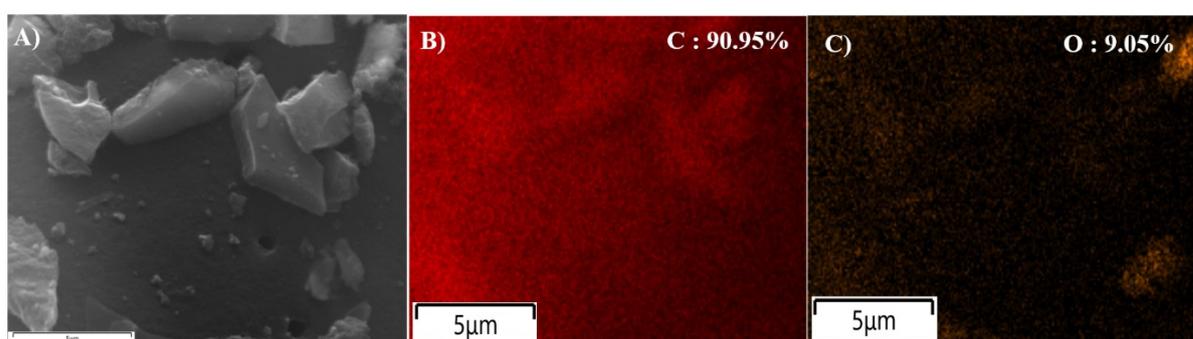
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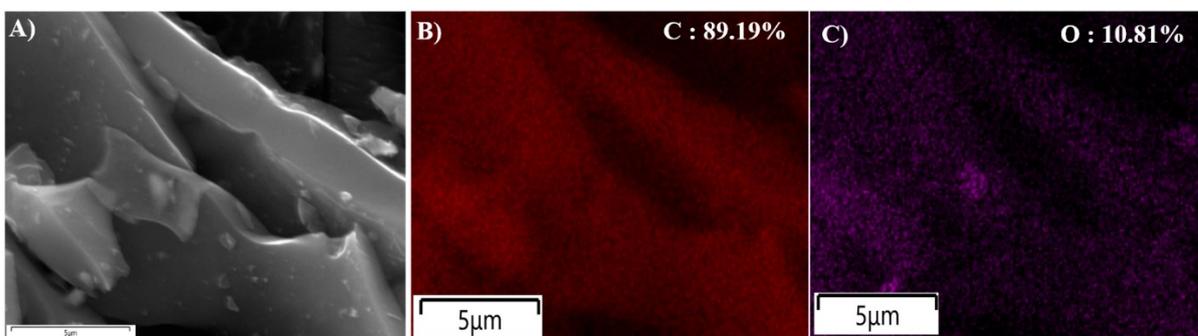
[epastor@ull.edu.es](mailto:epastor@ull.edu.es)



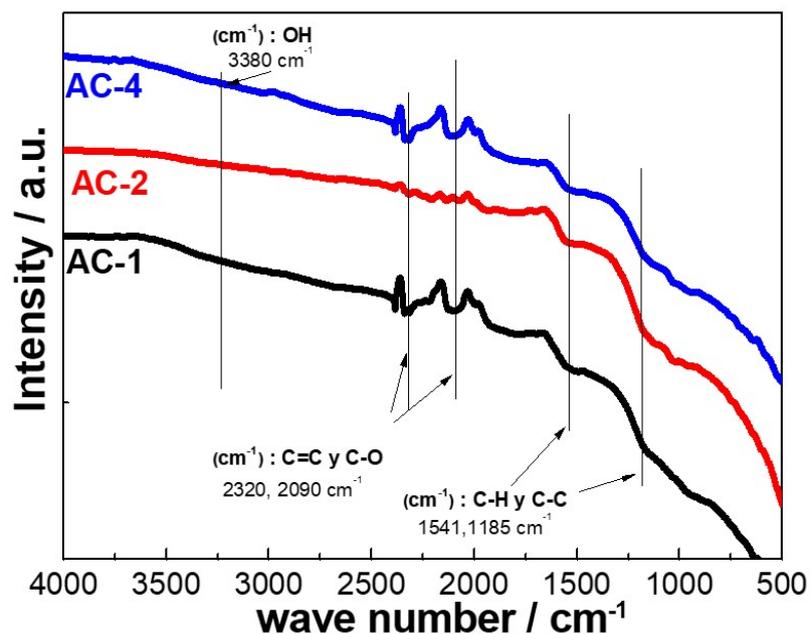
**Figure 1S.** A) SEM image of AC-1; EDX mapping of atoms B) Carbon and C) Oxygen



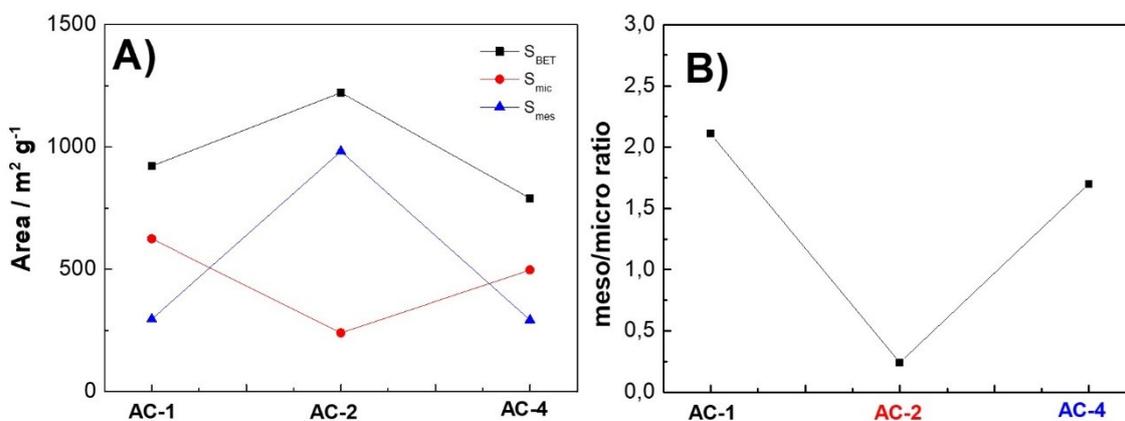
**Figure 2S.** A) SEM image of AC-2; EDX mapping of atoms B) Carbon and C) Oxygen



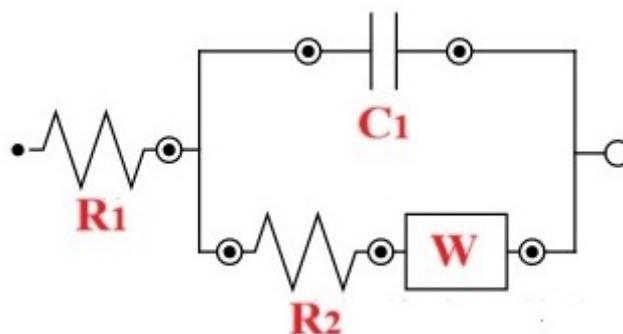
**Figure 3S.** A) SEM image of AC-4; EDX mapping of atoms B) Carbon and C) Oxygen.



**Figure 4S.** IR spectrum of the synthesized AC materials.



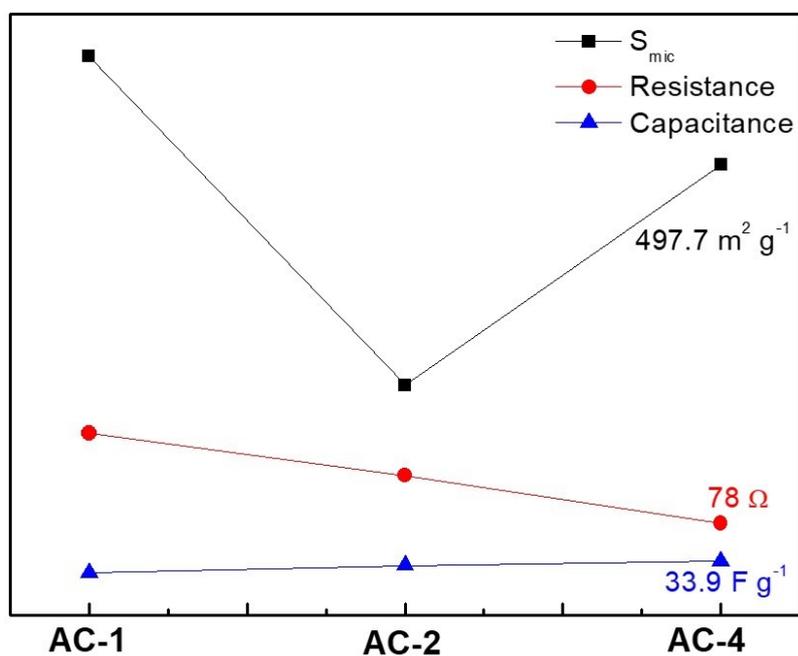
**Figure 5S.** A) Comparison of the different surface area contributions, including BET surface area ( $S_{\text{BET}}$ ), micropore area ( $S_{\text{micro}}$ ), and mesopore area ( $S_{\text{mes}}$ ), for the activated carbon samples AC-1, AC-2, and AC-4. B) Variation of the meso/micro pore area ratio, highlighting differences in pore structure balance among the materials.



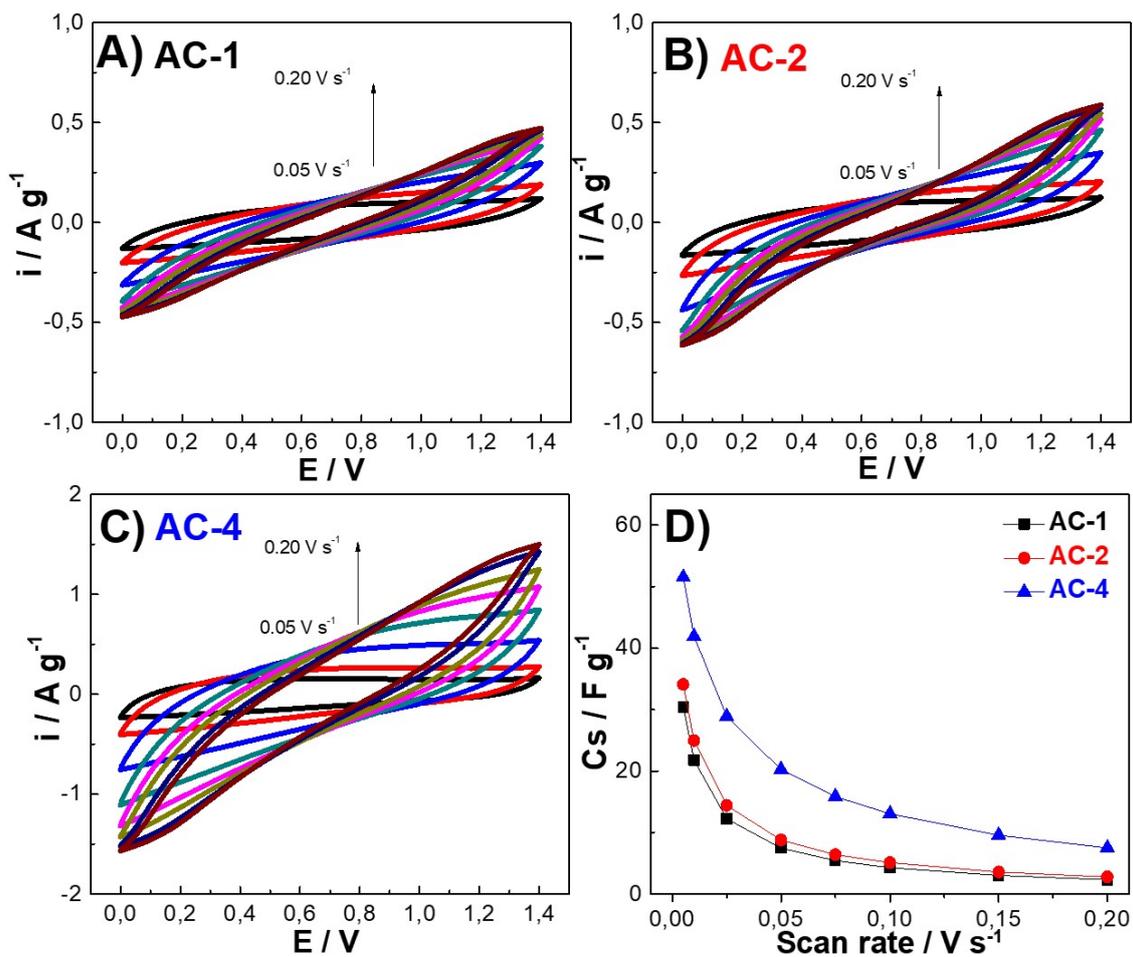
**Figure 6S.** Equivalent circuit obtained from EIS

**Table 1S.** Values of the elements of the equivalent circuit of the EIS

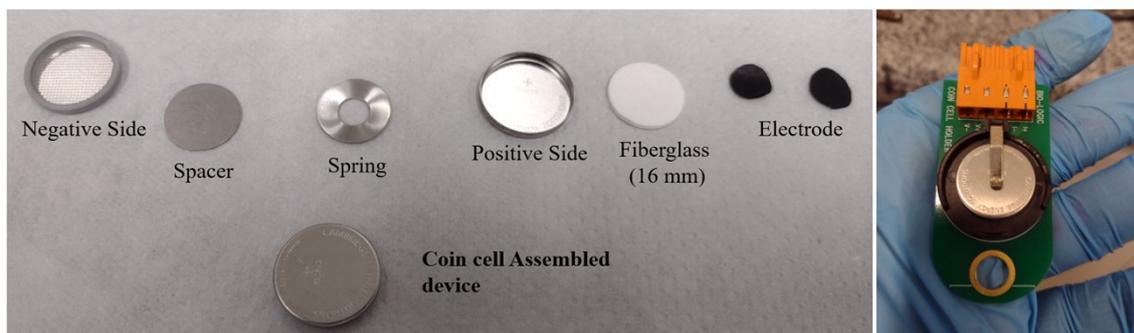
Materials	Elements							
	R1		C2		R2		W	
	Valor ( $\Omega$ )	Error (%)	Valor ( $\mu\text{F}$ )	Error (%)	Valor ( $\Omega$ )	Error (%)	Valor ( $\text{Mho}\cdot\text{s}^{1/2}$ )	Error (%)
AC-1	0.61	14.83	19.40	8.97	183.4	8.33	25.63	17.87
AC-2	0.64	16.03	13.79	9.65	133.6	5.57	24.63	16.34
AC-4	0.49	19.91	23.91	12.55	78.01	12.42	16.94	15.42



**Figure 7S.** Relationship between pore size distribution, diffusion resistance, and specific capacitance of the developed coin cells



**Figure 8S.** Analysis of devices **A)** AC-1, **B)** AC-2 and **C)** AC-4 at different scan rates (0.05 - 0.2  $V s^{-1}$ ) and **D)** Evaluation of specific capacitance ( $C_s$ ) ( $F g^{-1}$ ) versus different scan rates ( $V s^{-1}$ )



**Figure 9S.** Images of the parts and assembled coin cell device